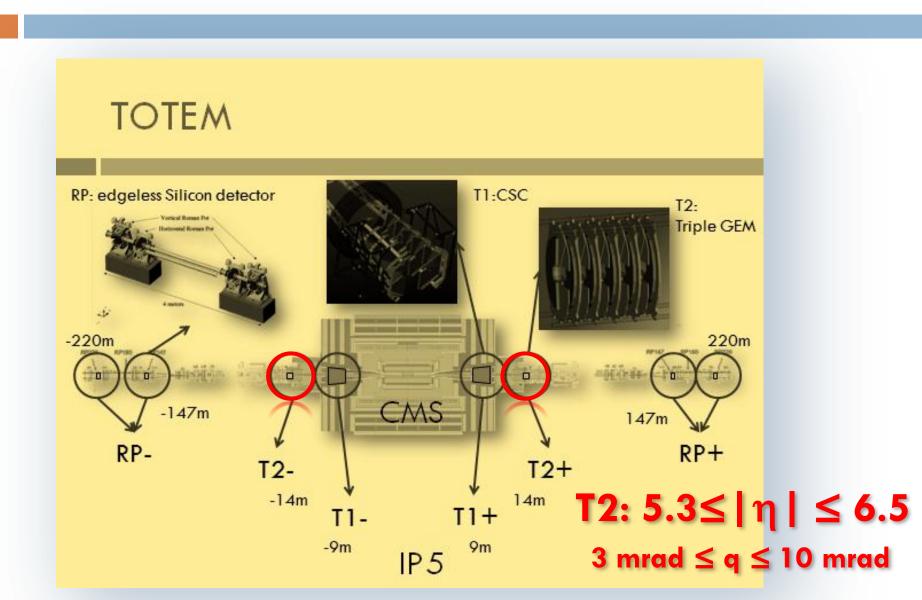
### TOTEM 2011 RD51 TEST BEAM

#### PnPR $\rightarrow$ PnP Transition in the TRIPLE GEM & VFAT2 SYSTEM

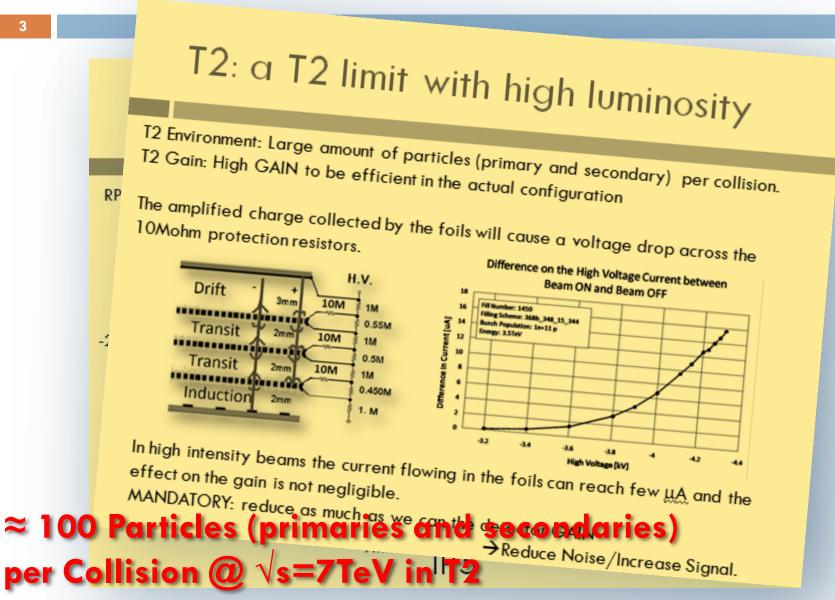
#### TOTEM Genova, Helsinki, Pisa-Siena Groups

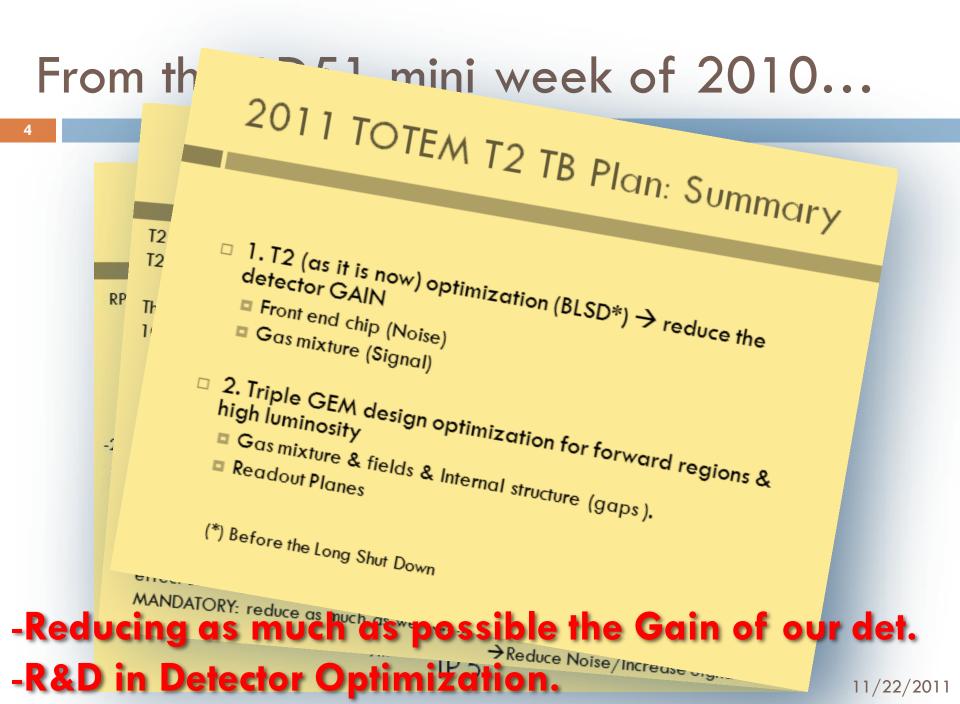
November 2011 – RD51 mini week – wg7

# From the RD51 mini week of 2010...



# From the RD51 mini week of 2010...





### Gain Reduction: Playing with the S/N Ratio

### 1. FE chip (VFAT2) Optimization.

Laboratory measurements had shown promising setting. Test beam data needed to confirm the goodness with the signal (efficiency and timing).

#### 2. Gas Mixture.

Faster Signal to better match the FE characteristics.

#### 3. Internal Structure

R&D studies on detector optimization. Internal gaps analyzed (induction and drift).







### $PnPR \rightarrow PnP$ Transition in the Triple GEM & VFAT2

#### PnPR (Plug and PRAY)

#### PnP (Plug and PLAY)



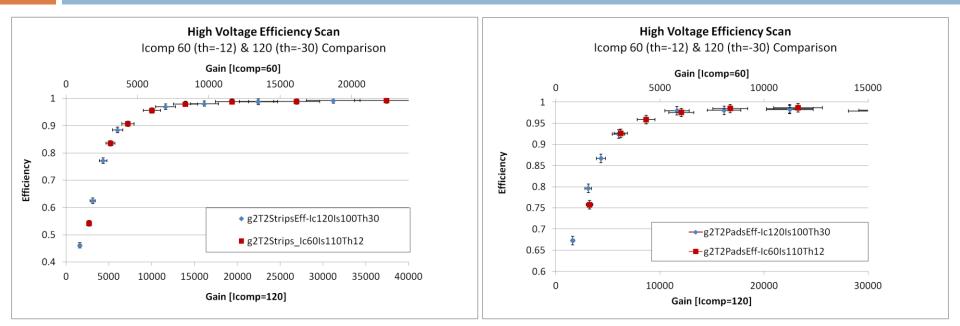


**BEFORE ICOMP** 

AFTER ICOMP

The new settings represents for us the passage from a "plug and pray" chip to a "plug and play" one.

### VFAT2 Settings: Internal Comparator Current



#### Gain Reduction Factor:

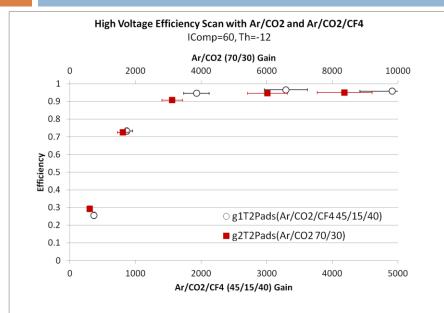
Icomp Register std value :120 Lowered down to 40 preserving a good behavior

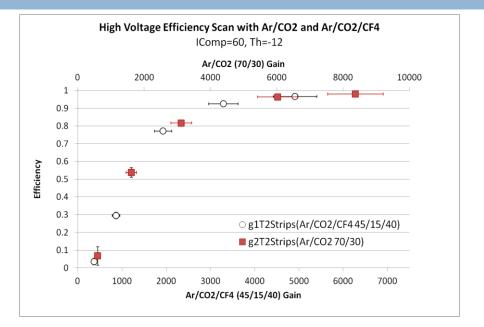
T2TripleGEM in H8: 1.5(strips)/2(pads)

(result referred to a silent detector)

Roughly all threshold in IP5 >40/45@ lcomp75 (here we have 30 @ lc120) We could expectT2TripleGEM in IP5: 3/5(?)/...(??)

## Gas Mixture: from Ar/CO2 to Ar/CO2/CF4





Gain Reduction Factor:

#### Faster Signal, better VFAT2 response

Ar/CO2/CF4 (45/15/40): Ar/CO2/CF4 (60/20/20):

### 1.3(strips)/2(pads)

1.3(pads) [2010 RD51 H4 test beam data on Large GEM]

Going from 2mm to 1mm Induction gap:  $\frac{2}{3(?)}/4(??)$ 

### Internal Structure : Drift Gap

Drift gaps of 2mm or 1mm are obviously less efficient but we would like to cut away the signal "notefficiently used" by our FE

High Voltage Efficiency Scan with a Drift Gap of 3mm and 1mm Icomp 60 (th=-12) gCTL [1mm Drift Gap] Gain 0 5000 10000 15000 20000 25000 30000 35000 40000 45000 50000 1 0.9 \_**=** 0.8 Ħ 0.7 ------0.6 HH-Efficiency 0.5 ± g1T2Strips\_Eff 0.4 gCTLMiddleLeft\_Eff 0.3 × gCTLTopMiddle\_Eff 0.2 0.1 No Improvement with 0 5000 10000 0 Ar/CO2 (70/30) g1T2Strips [3mm Drift Gap] Gain **Gain Reduction Factor:** ... with CF4? 2012 tb...

No Gain Reduction Observed with Ar/CO2.

Compensation of the missing charge needed (i.e. increasing the detector Gain)

#### 11/22/2011

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### Summary

- Gain Reduction Factor in T2 as it is:
  - VFAT Setting:

3/5/...

- Gas Mixture (+CF4):
- Drift Gap:

No Improvement

1.5/2...

TOTAL GAIN REDUCTION: between 3 and 10 (or hopefully higher, depending on the detector noise level)

- Trying to push more... new detectors...
  - Imm Induction  $1.5/2(CF4) \rightarrow 2/3/4(?)$
  - 2/1 mm Drift & CF4 (???)

The achieved results are good but an effort on design a new high voltage divider (with a particular attention on the protection circuit) is nevertheless needed to guarantee our operation ( $5.3 \le |\eta| \le 6.5$ ) in the high luminosity LHC environment.

# 2012 RD51 TB

- □ 1. FE chip (VFAT2) Optimization.
  - Other settings still untouched...
  - VFAT2 & SRS System (different Hybrid & Powering Configuration... interesting for us to understand if there is any improvement).
- 2. Test on TOTEM T2 with a new HV divider (different solution for the actual protection resistors and new internal field optimized for mixtures with CF4) to will be replaced during the LHC long shut down.
- 3. R&D on different Internal Structures: Gaps & Gas.

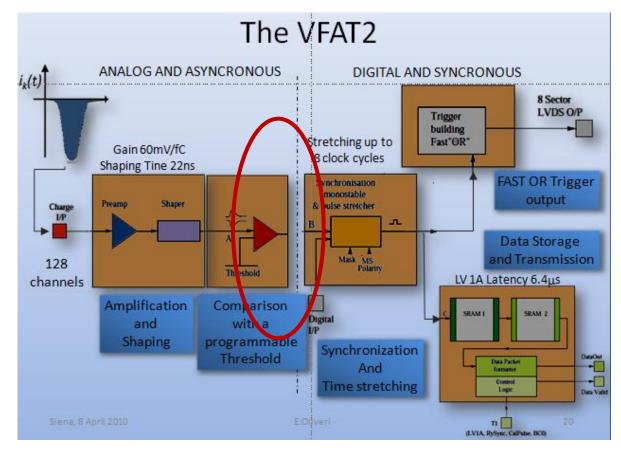
## A little bit more on the FE chip (VFAT2) Optimization

(just because it has been the most promising item and it could help other VFAT2 users )

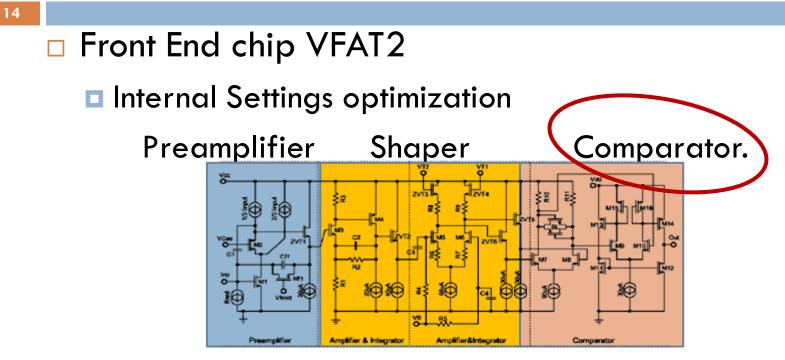
### Noise Improvement: VFAT2 Settings

### Front End chip VFAT2

#### Internal Settings optimization: The Comparator Current



### Noise Improvement: VFAT2 Settings

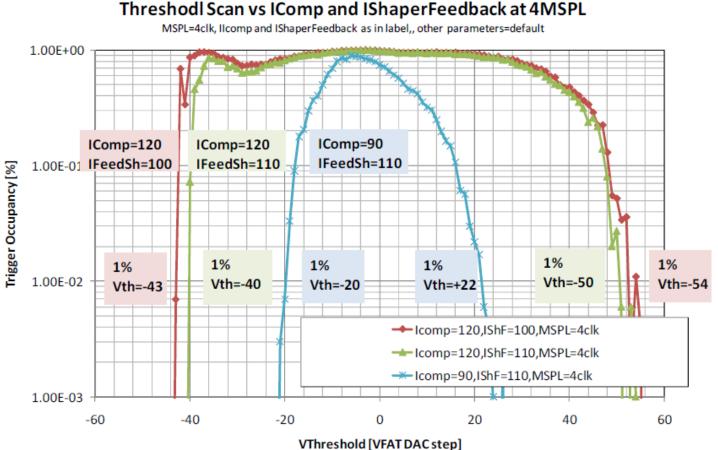


- Reducing the Internal Comparator Current we observed:
  - 1.1 <u>Noise Reduction (mainly the cross talk components ever</u> observed in 2D readout).
  - 1.2 <u>Signal Attenuation</u> (negligible respect with the noise reduction)
  - 1.3 <u>Time Resolution not affected</u>.

### VFAT2 Settings: IComp & Noise (lab)

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#### $\square$ Lab Test: Effects of IComp on the Noise $\rightarrow$ Threshold Scan



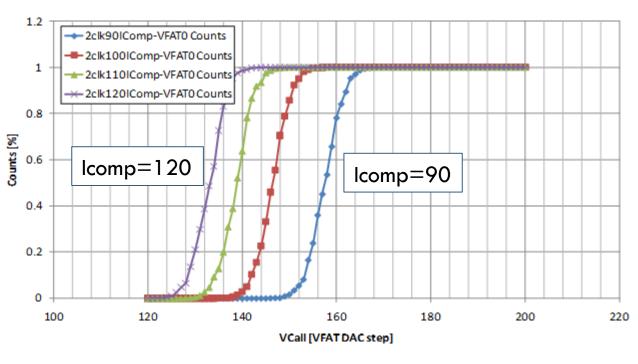
### VFAT2 Settings: IComp & Signal(Iab)

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### □ Lab Test: Effects of IComp on the Signal → Calibration Scan (S Curve)

Calibration Pulse Scan

MSPL=2clk, Latency=126, Threhsold=-120, I Comp=90, 100, 110, 120, other VFATs parameters=default



VFAT2 Internal Amplification Reduced.

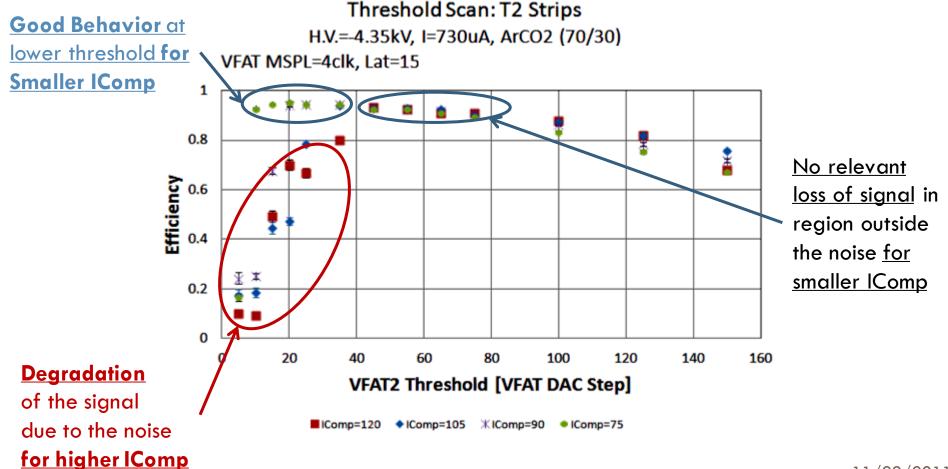
The loss of internal gain is however <u>negligible compared</u> with the improvement offered by the noise reduction.

Slow signals (compared to the cal pulse) as the one of our gas detector, are moreover less affected by this loss of signal.

### VFAT2 Settings: IComp & Signal(beam)

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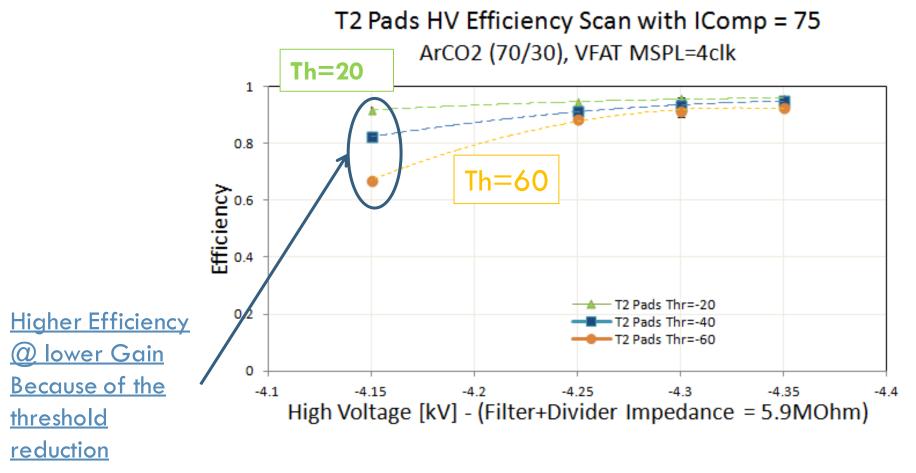
#### H8 Beam: Efficiency vs Threshold for different IComp



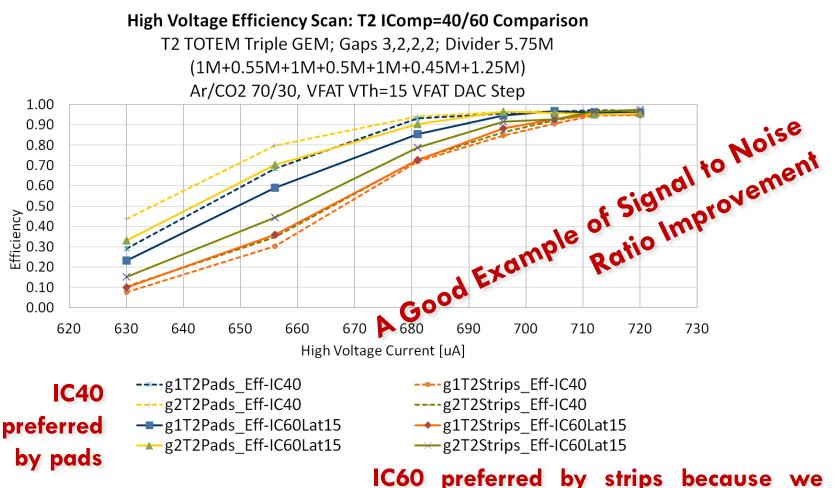
### VFAT2 Settings: IComp & Signal(beam)

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#### □ H8 Beam: Efficiency vs HV for different Threhsold



### VFAT2 Settings: Icomp & S/R optimization

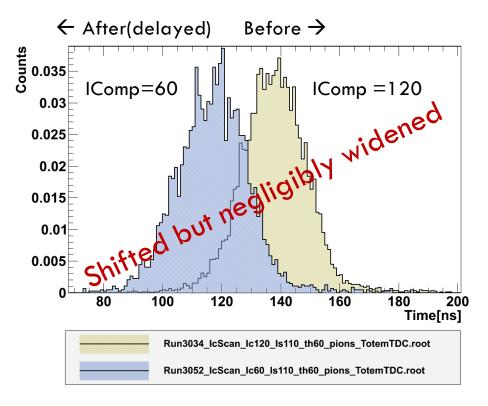


cannot reduce the threshold as for pads

### VFAT2 Settings: IComp & Timing(beam)

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#### H8 TB Data: IComp Effects on the Timing of the Signal



TDC Measurement: No degradation of the timing performance of the FE+T2GEM system.

<u>Reducing IComp, we observed an offset</u> (delay) but the effects on the time resolution was negligible (same RMS)

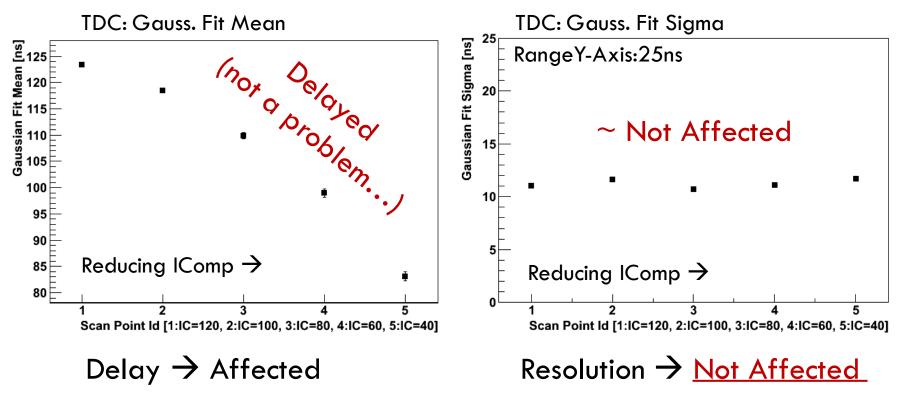
We measured the difference in time between the VFAT2 Trigger SBit Signal and the Scintillators Coincidence. (higher distribution mean means before in time in our set up).

### VFAT2 Settings: IComp & Timing(beam)

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#### H8 TB Data: Timing and VFAT2 Comparator Current

Ar/CO270/30



### VFAT2 cross talk in 2D readout

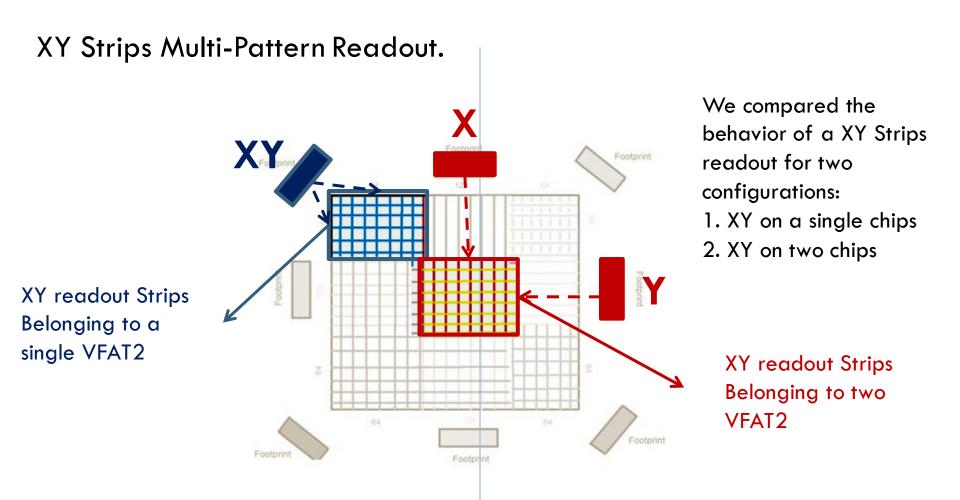
## Powering and grounding ... a key point

### VFAT2 Powering/Grounding

- A Multi Pattern Readout Board has been designed to understand the role played by the FE chip and/or the readout pattern in the observed <u>cross talk noise</u>.
- The performed measurement <u>address the observed cross talk</u> to the FE powering and grounding (different power/ground fluctuation between different chips inject noise through the coupling provided by the readout).
- Possible Improvement: <u>redesigning of the FE hybrid and of the FE powering/grounding scheme.</u>

### FE Powering/Grounding Optimization

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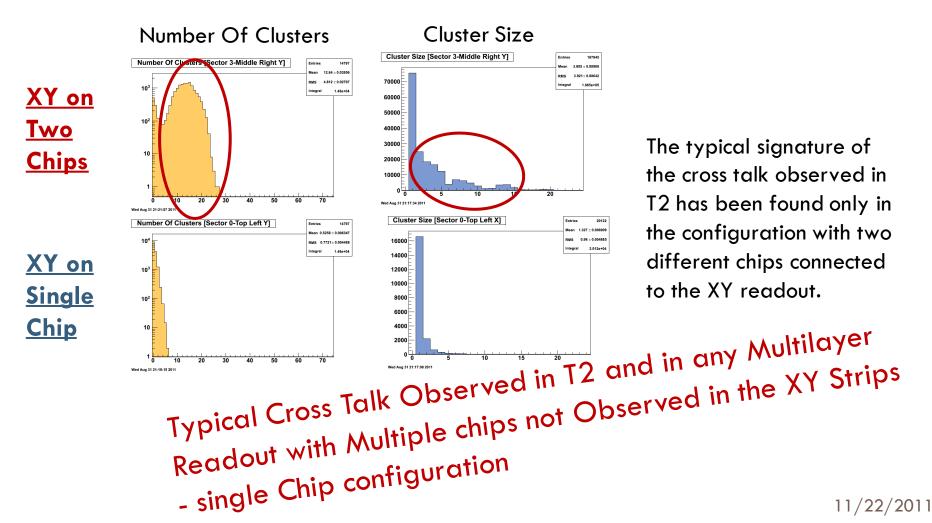


[Readout designed/provided by Helsinki Group: F. Garcia Fuentes]

### FE Powering/Grounding Optimization

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Number of Clusters and Cluster Size at low threshold (partially inside the noise)



## thanks